

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/617,259	<b>Applicant(s)/Patent under Reexamination</b> NA ET AL.
	<b>Examiner</b> German Viana Di Prisco	<b>Art Unit</b> 2616

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST Image and keyword search in USPAT, US-PGPUB, DERWENT,EPO,JPO and IBM_TDB (see attached search strategy)	9/14/2007	GV
Inventor name and Assignee search in PALM ExPO and EAST	9/14/2007	GV
EPO Database( <a href="http://ep.espacenet.com">http://ep.espacenet.com</a> )	9/14/2007	GV
KIPODatabase ( <a href="http://www.kipo.go.kr">http://www.kipo.go.kr</a> )	9/14/2007	GV
Consulted with Ken Vanderpuye and Steven Nguyen		
congest\$3 with (compress\$3 full) with (header packet)		